## Notice of References Cited Application/Control No. 10/574,131 Examiner David N. Werner Applicant(s)/Patent Under Reexamination YANAI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-5,574,443 A	11-1996	Hsieh, Chi-Sheng	340/901	
*	В	US-4,214,266	07-1980	Myers, Charles H.	348/140	
*	С	US-5,670,935 A	09-1997	Schofield et al.	340/461	
*	D	US-5,959,555 A	09-1999	Furuta, Yoshihisa	340/937	
*	Е	US-6,476,855 B1	11-2002	Yamamoto, Yasuhide	348/148	
	F	US-				
	G	US-				
	Н	US-				
	1	US-				
	J	US-				
	К	US-				
	L	US-				
	М	US-				

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.